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| Substitute Form PTO-1449 (Modified) | | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 10559-678002 | Application No. 10/620,829 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) | | Applicant Keshavarzi et al. | | |
| | | Filing Date July 16, 2003 | Group Art Unit | |

| U.S. Patent Documents | | | | | | | |
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| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
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| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |
| | | | | | | | Yes No |
| | AK | | | | | | |
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| Examiner Signature <i>/Thanh X Luu/</i> | Date Considered <i>04/23/2007</i> |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |